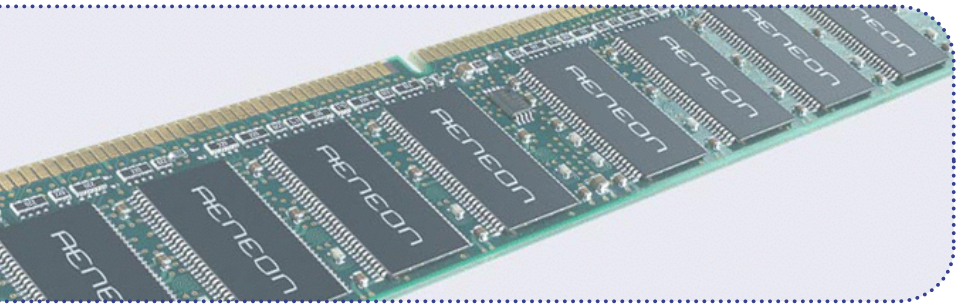

Simply advanced

Small-Outline Memory Module
Data Sheet

AET660SD00-370

512 MByte DDR2–533 200-Pin SO-DIMM

Description

This data sheet describes features and specification of AENEON™ memory module family AET660SD00-370. The four digit product type postfix is for internal logistic purposes.

Features

- 512 MByte organized as 64 M x 64 bit
- Double Data Rate Two SDRAM components
- Speed grade DDR2–533 CL4 on component level
- Provides up to 4264 MByte per second on module level
- Module Code PC2–4200S–444–12
- 200-Pin Dual Inline Memory Module (DIMM) with gold contacts
- Fitting in industry standard motherboards

Specification

Parameter	Values
Clock cycle time t_{CK} for CL4	3.75 ns (min.) / 8 ns (max.)
Clock cycle time t_{CK} for CL3	5 ns (min.) / 8 ns (max.)
Row cycle time t_{RC}	60 ns (min.)
Refresh row cycle time t_{RFC}	105 ns (min.)
Activate to read/write delay t_{RCD}	15 ns (min.)
Row active time t_{RAS}	42 ns (min.) / 70.000 ns (max.)
Single power supply V_{DD} = V_{DDQ}	1.8 V ± 0.1 V
Operating power I_{DD0}	0.8 W (max.)
Module dimensions L x W x H	67.6 mm x 30.0 mm x 2.7 mm (max.)
	2.66" x 1.18" x 0.11" (max.)

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1. A failure of the AENEON Products can reasonable be expected to –directly or indirectly–
   a. Have a detrimental effect on such Critical Systems in terms of reliability, effectiveness or safety; or
   b. Cause the failure of such Critical Systems; or
2. A failure or malfunction of such Critical Systems can reasonably be expected to –directly or indirectly–
   a. Endanger the health or the life of the user of such Critical Systems or any other person; or
   b. Otherwise cause material damages (including but not limited to damages or serious injury to life or property, whether tangible or intangible).